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PATENT APPLICATION
Docket No. 8750-017
Client No. SPX200110-0010US

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

CERTIFICATE OF MAILING UNDER 37 CFR 1.8

I HEREBY CERTIFY THAT THIS CORRESPONDENCE IS BEING DEPOSITED WITH THE UNITED STATES POSTAL SERVICE WITH SUFFICIENT POSTAGE AS FIRST CLASS MAIL IN AN ENVELOPE ADDRESSED TO MAIL STOP RCE, COMMISSIONER FOR PATENTS, P.O. BOX 1450, ALEXANDRIA, VA 22313-1450 ON MARCH 16, 2004.

ADRIENNE CHOCHOLAK
(SENDER'S PRINTED NAME)


(SIGNATURE)

In re application of: Sang-Eun Lee and JAe-Sung Han

Serial No. 10/068,152

Examiner: Hollington, Jermele M.

Confirmation No. 7500

Filed: February 6, 2002

Art Unit: 2829

For: METHOD OF IDENTIFYING AND ANALYZING
SEMICONDUCTOR CHIP DEFECTS

REQUEST FOR CONTINUED EXAMINATION (RCE) TRANSMITTAL

MAIL STOP RCE
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

This is a Request for Continued Examination (RCE) under 37 C.F.R. § 1.114 of the above-identified application.

1. Submission required under 37 C.F.R. § 1.114

a. ☐ Previously submitted:

☐ Consider the amendment(s) reply under 37 C.F.R. §1.116 previously filed on _____.

b. ☒ Enclosed is: | 03/22/2004 JADD01 00000075 10068152

☒ Amendment/Reply 01 FC:1801 770.00 OP
02 FC:1253 950.00 OP

2. Miscellaneous

☐ Suspension of action on the above-identified application is requested under 37 C.F.R. § 1.103(c) for a period of _____ months. (Period of suspension shall not exceed 3 months; fee under 37 C.F.R. § 1.17(i) required).

3. **Fees:** (Note: The RCE fee under 37 C.F.R. §1.17(e) is required by 37 C.F.R. §1.114 when the RCE is filed)

☒ RCE fee required under 37 C.F.R. § 1.17(e)

☒ \$770 large entity

☒ Extension of time fee (37 C.F.R. §§1.136 and 1.17)

☒ Extension of Time - 3rd small entity large entity
 ☐ \$475 ☒ \$950

☒ PTO Form 2038 authorizing credit card payment of \$1720.00, filing fee (\$770.00) and extension fee (\$950.00) is enclosed

☒ Any deficiency or overpayment should be charged or credited to deposit account number 13-1703.

Customer No. 20575

Respectfully submitted,

MARGER JOHNSON & McCOLLOM, P.C.



Alan T. McCollom
Reg. No. 28,881

MARGER JOHNSON & McCOLLOM, P.C.
1030 SW Morrison Street
Portland, OR 97205
503-222-3613



PATENT APPLICATION
Docket No. 8750-17
Client No. SPX2001100010US

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of: Sang-Eun Lee and Jae-Sung Han

Serial No. 10/068,152 Examiner: Hollington, Jermele M.

Confirmation No. 7500

Filed: February 6, 2002 Art Unit: 2829

For: METHOD OF IDENTIFYING AND ANALYZING
SEMICONDUCTOR CHIP DEFECTS

Mail Stop RCE
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

AMENDMENT

Responsive to the final Office Action mailed 25 September 2003 and the Advisory Action mailed 27 February 2004, please amend the application as follows.

Amendments to the Claims are reflected in the listing of claims which begins on page 2 of this paper.

Remarks/Arguments begin on page 6 of this paper.